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Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/005,193	CHEN ET AL.	
Examiner	Art Unit	_

2162

Fred I. Ehichioya

SEARCHED			
Class	Subclass	Date	Examiner
707	5, 6, 102, 103R, 104.1	4/6/2006	FE
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
707	5, 102	4/6/2006	FE
707	103R	4/6/2006	FE
707	104.1	4/6/2006	FE

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Search	4/6/2006	FE
Google.com	4/6/2006	FE
ACM Digital Library	4/6/2006	FE
EIC	4/14/2006	FE
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